## Notice of References Cited Application/Control No. 10/608,198 Examiner Mark A. Osele Applicant(s)/Patent Under Reexamination TAMAI ET AL. Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0179242	12-2002	Wien, Thomas M.	156/344
*	В	US-2001/0053644	12-2001	Doniger, Neil A.	442/59
*	С	US-5,282,631	02-1994	Baker, Dorothee A.	273/272
*	D	US-2,387,512	10-1945	HILBERG FRANK C	250/462.1
*	E	US-RE28,732	03-1976	von Hofe, George W.	156/64
*	F	US-5,968,244	10-1999	Ueda et al.	106/31.86
*	G	US-5,962,137	10-1999	Ochiai et al.	428/411.1
*	Н	US-2002/0033237	03-2002	Narita et al.	156/577
*	1	US-5,430,904	07-1995	Ono et al.	15/104.94
*	J	US-5,795,085	08-1998	Yoo, Kwang-Ho	400/248
*	K	US-6,363,990	04-2002	Kozaki, Hiroshi	156/540
*	L	US-6,187,432	02-2001	Krish et al.	428/343
*	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
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	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
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	x		

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.